Icemos Technology Ltd Product Specification 1003.697301 Issue Date 06 October 2021 14:1

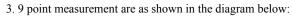
Part Number	Customer	

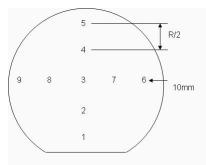
Category		Parameter	Specification	Measurement Method
OverallWafer	1.0	Silicon Supplier	Change Authorisation Agreement with Philips - No material change RM/TOOLING etc without prior approval of Philips.	
	2.0	Diameter	200.00 +/- 0.20 mm	Wafer Vendor
	3.0	Notch Direction	{110}+/-1.0 degree	Wafer Vendor
	4.0	Notch or Flat	Notch	Wafer Vendor
	5.0	Secondary Flat Orientation	none	
	6.0	Overall Thickness	500.00 +/- 2.00 μm	ADE, 100%
	7.0	Total Thickness Variation (TTV)	<3.00μm	Guaranteed by Process
	8.0	Bow	<40.00μm	ADE to ASTM F534, 20%
	9.0	Warp	<40.00μm	ADE to ASTM F657, 20%
	10.0	Edge Chips	0	Bright Light, 100% (note 2)
	11.0	Edge Exclusion	5mm	
HandleSilicon	12.0	Handle Growth Method	CZ	Wafer Vendor
	13.0	Handle Orientation	{100} +/- 0.5 degree	Wafer Vendor
	14.0	Handle Thickness	500.00 +/- 2.00 μm	ADE, 100%
	15.0	Handle Doping Type	Any	Wafer Vendor
	16.0	Handle Dopant	Any	Wafer Vendor
	17.0	Handle Resistivity	$2 \sim 10 \text{ Ohmcm}$	Wafer Vendor
	18.0	Backside Finish	Polished with light handling marks & lasermarking	Guaranteed by process
	19.0	Total scratch length	Front side - 10mm total accumulated length.	Bright Light, 100% (note 2)
	20.0	Surface Haze	Front side - None	Bright Light, 100% (note 2)
OverallWafer	21.0	LPDs > 0.3um	<60 count >0.3um diameter.	Tencor Particle counter

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Part Number		Customer		
Category	Parameter	Specification	Measurement Method	
Shipping Details	Wafer per box :	Max 25		
	Packaging:	Taped Polypropylene Wafer Box Empak, Ultrapak, 200.00mm Antistatic Double Bagging		
	Lot Shipment Data	Device Thickness Bow / Warp Data Handle and SOI Thickness		
Explanatory Notes	1. Microscope inspec	tion performed using microscope scan as below. 5x objective.		
	2. All bright light inspections performed exclude all wafer area outside the edge exclusion defined in Overall Wafer, Edge Evolusion, High intensity bright, lamp inspection as per ASTM E523			

Wafer, Edge Exclusion. High intensity bright lamp inspection as per ASTM F523.





Additional Information